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PATENT
8001-1158-1

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Rieka OHUCHI Conf. 3792

Application No. 10/659,383 Group 2812

Filed September 11, 2003

SEMICONDUCTOR DEVICE AND METHOD
OF MANUFACTURING THEREOF

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

August 10, 2004

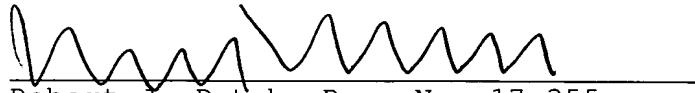
Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.

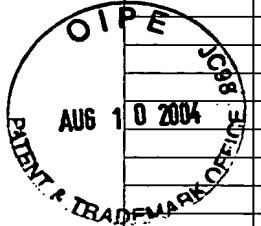
A concise explanation of the relevance of these items is that these references were cited by the Japanese Patent Office in an Official Action. A copy of the Japanese Official Action in which they were cited is attached hereto, with what is believed to be the pertinent portion enclosed in a wavy line. **An English translation of the enclosed portion is also attached hereto.**

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Attorney Docket No.: 8001-1158-1		Application No.: 10/659,383		
		Applicant: Rieka OHUCHI				
		Filing Date: September 11, 2003		Group Art Unit: 2812		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)
 (This row is intended for listing U.S. Patent Documents, which is currently empty.)						
FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
						Yes
	JP 5-144878	6/11/1993	JAPAN			
	JP 2000-77472	3/14/2000	JAPAN			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER:		DATE CONSIDERED				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

* Abstract provided for the Examiner's convenience